

Notice of References Cited	Application/Control No. 10/612,940	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Jean F. Duverne	Art Unit 2839	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,851,221 A	12-1998	Rieder et al.	607/93
	B	US-5,897,578 A	04-1999	Wiklund et al.	607/36
	C	US-5,919,215 A	07-1999	Wiklund et al.	607/36
	D	US-6,205,358 B1	03-2001	Haeg et al.	607/36
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.